

**Circuits  
from the Lab™**  
Reference Circuits

*Circuits from the Lab™ reference circuits are engineered and tested for quick and easy system integration to help solve today's analog, mixed-signal, and RF design challenges. For more information and/or support, visit [www.analog.com/CN0150](http://www.analog.com/CN0150).*

**Devices Connected/Referenced**

<b>AD8318</b>	1 MHz to 8 GHz, 70 dB, Logarithmic Detector/Controller
<b>AD7887</b>	2.7 V to 5.25 V, Micropower, 2-Channel, 125 kSPS, 12-Bit ADC in 8-Lead MSOP
<b>ADR421</b>	Precision, Low Noise, 2.5 V Reference

**Software-Calibrated, 1 MHz to 8 GHz, 60 dB RF Power  
Measurement System Using a Logarithmic Detector**

**EVALUATION AND DESIGN SUPPORT**

**Circuit Evaluation Boards**

- [CN-0150 Circuit Evaluation Board \(EVAL-CN0150A-SDPZ\)](#)
- [System Demonstration Platform \(EVAL-SDP-CB1Z\)](#)

**Design and Integration Files**

- [Schematics, Layout Files, Bill of Materials](#)

**CIRCUIT FUNCTION AND BENEFITS**

This circuit measures RF power at any frequency from 1 MHz to 8 GHz over a range of approximately 60 dB. The measurement result is provided as a digital code at the output of a 12-bit ADC with serial interface and integrated reference. The output of the RF detector has a glueless interface to the ADC and uses most of the ADC's input range without further adjustment.

A simple two-point system calibration is performed in the digital domain.

The **AD8318** maintains accurate log conformance for signals of 1 MHz to 6 GHz and provides useful operation to 8 GHz. The device provides a typical output voltage temperature stability of  $\pm 0.5$  dB.

The **AD7887** ADC can be configured for either dual or single channel operation via the on-chip control register. There is a default single-channel mode that allows the **AD7887** to be operated as a read-only ADC, thereby simplifying the control logic.

Typical data is shown for the two devices operating over a  $-40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$  temperature range.

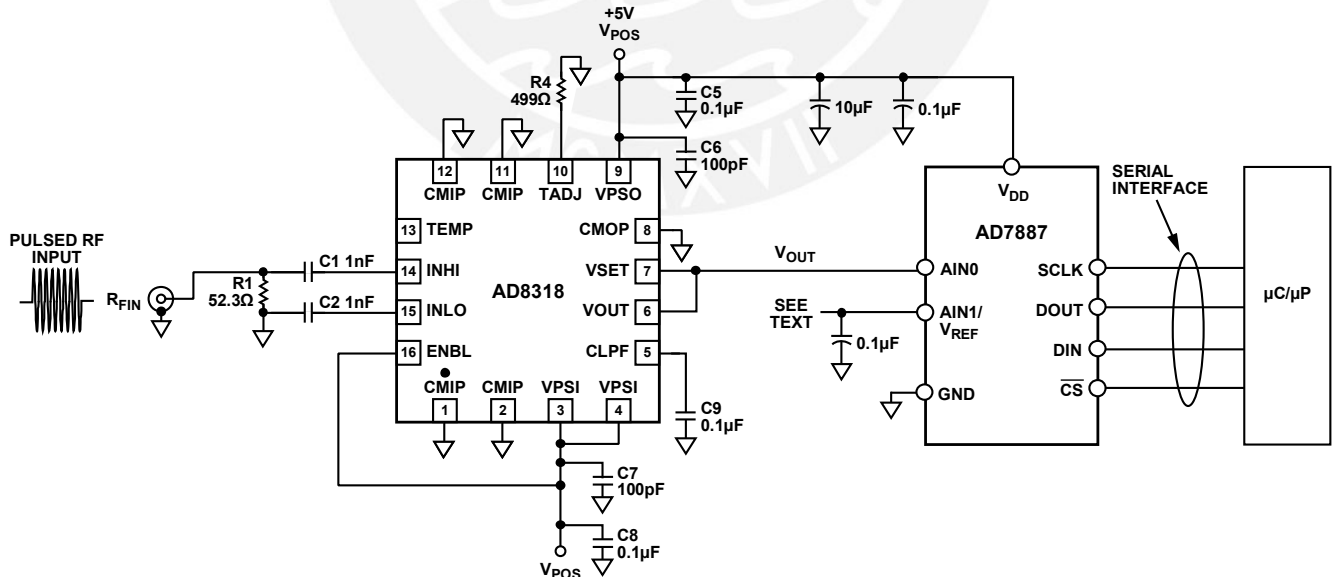


Figure 1. Software-Calibrated RF Measurement System (Simplified Schematic: All Connections Not Shown)

**Rev. C**

Circuits from the Lab™ circuits from Analog Devices have been designed and built by Analog Devices engineers. Standard engineering practices have been employed in the design and construction of each circuit, and their function and performance have been tested and verified in a lab environment at room temperature. However, you are solely responsible for testing the circuit and determining its suitability and applicability for your use and application. Accordingly, in no event shall Analog Devices be liable for direct, indirect, special, incidental, consequential or punitive damages due to any cause whatsoever connected to the use of any Circuits from the Lab circuits. (Continued on last page)

One Technology Way, P.O. Box 9106, Norwood, MA 02062-9106, U.S.A.  
 Tel: 781.329.4700 [www.analog.com](http://www.analog.com)  
 Fax: 781.461.3113 ©2010–2012 Analog Devices, Inc. All rights reserved.

**CIRCUIT DESCRIPTION**

The RF signal being measured is applied to the AD8318. The device is configured in its so-called measurement mode, with the VSET and VOUT pins connected together. In this mode, the output voltage vs. the input signal level is linear-in-dB (nominally -24 mV/dB) and has a typical output voltage range of 0.5 V to 2.1 V.

The AD8318 output is connected directly to the AD7887, 12-bit ADC. The ADC uses its internal reference and is configured for a 0 V to 2.5 V input, resulting in an LSB size of 610 μV. With the RF detector providing a nominal -24 mV/dB, the digital resolution is 39.3 LSBs/dB. With this much resolution, there is little value in trying to scale the 0.5 V to 2.1 V signal from the RF detector to exactly fit the 0 V to 2.5 V range of the ADC.

The transfer function of the detector can be approximated by the equation

$$V_{OUT} = SLOPE \times (P_{IN} - INTERCEPT)$$

where SLOPE is in mV/dB (-24 mV/dB nominal); INTERCEPT is the x-axis intercept with a unit of dBm (20 dBm nominal); and P<sub>IN</sub> is the input power expressed in dBm. A typical plot of detector output voltage vs. input power is shown in Figure 2.

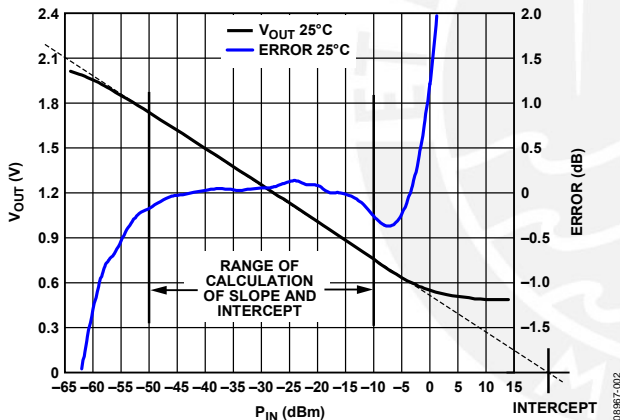


Figure 2. Typical Output Voltage vs. Input Signal Level for the AD8318

At the output of the ADC, the equation can be written as

$$CODE\_OUT = SLOPE\_ADC \times (PIN - INTERCEPT)$$

where SLOPE\_ADC is in codes/dB and PIN and INTERCEPT are in dBm. Figure 3 shows a typical detector power sweep in terms of input power and observed ADC codes.

Because the slope and intercept of the system vary from device to device, a system level calibration is required. A calibration is performed by applying two known signal levels close to the endpoints of the AD8318 linear input range and measuring the corresponding output codes from the ADC. The calibration points chosen should be well within the linear operating range of the device (-10 dBm and -50 dBm in this case).

Using the two known input power levels, PIN<sub>1</sub> and PIN<sub>2</sub>, and the corresponding observed ADC codes, CODE<sub>1</sub> and CODE<sub>2</sub>, SLOPE\_ADC, and INTERCEPT can be calculated using the following equations:

$$SLOPE\_ADC = (CODE\_2 - CODE\_1) / (PIN\_2 - PIN\_1)$$

$$INTERCEPT = PIN\_2 - (CODE\_2 / SLOPE\_ADC)$$

Once SLOPE\_ADC and INTERCEPT are calculated and stored (in nonvolatile RAM) during factory calibration, they can be used to calculate an unknown input power level, PIN, when the equipment is in operation in the field using the equation

$$PIN = (CODE\_OUT / SLOPE\_ADC) + INTERCEPT$$

Figure 3 through Figure 8 show how the system transfer function deviates from this straight line equation, particularly at the endpoints of the transfer function. This deviation is expressed in dB using the equation

$$Error (dB) = Measured Input Power - True Input Power = (CODE\_OUT / SLOPE\_ADC) + INTERCEPT - PIN\_TRUE$$

where:

CODE\_OUT is the ADC output code.

SLOPE\_ADC is the stored ADC slope in codes/dB.

INTERCEPT is the stored intercept.

PIN\_TRUE is the exact (and unknown) input level.

The plots shown in Figure 3 through Figure 8 show the typical system performance that can be obtained using the AD8318 and AD7887BR in an RF power measurement system. The graphs depict the RF input power in dBm vs. the ADC output code and output error in dB (scaled on the axes on the right side of the plots). They were generated from data taken with various input power levels, frequencies, and temperatures and with both internal and external ADC voltage references. The charts show improved system performance and lower temperature drift with the use of a low drift external ADC voltage reference. (See the Common Variations section for more details about the use of an external reference.

A complete design support package for this circuit note can be found at [www.analog.com/CN0150-DesignSupport](http://www.analog.com/CN0150-DesignSupport).

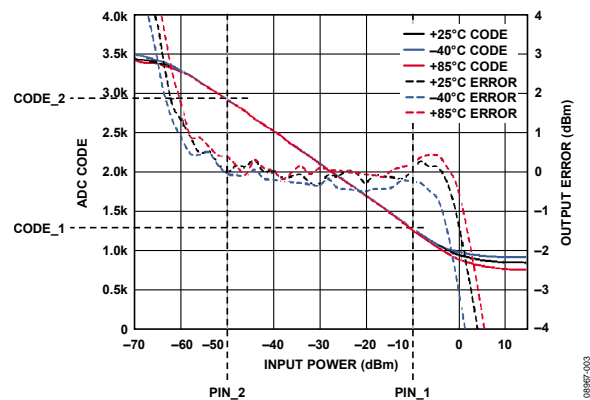


Figure 3. Input = 900 MHz, ADC Using an Internal 2.5 V Reference

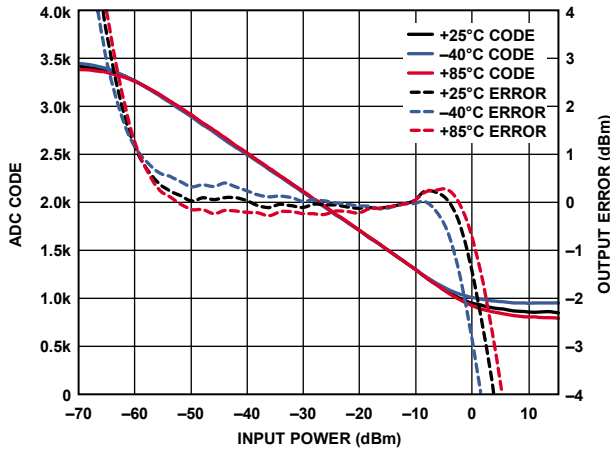


Figure 4. Input = 900 MHz, ADC Using an External 2.5 V Reference

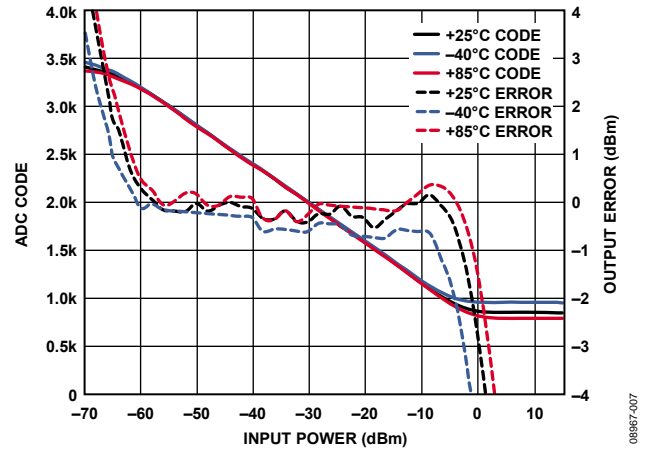


Figure 7. Input = 2.2 GHz, ADC Using an Internal 2.5 V Reference

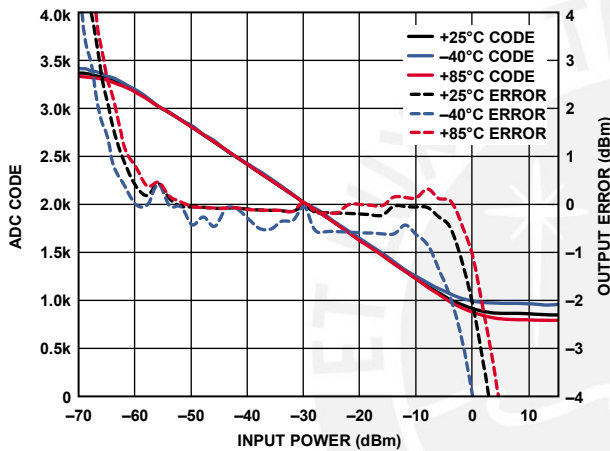


Figure 5. Input = 1.9 GHz, ADC Using an Internal 2.5 V Reference

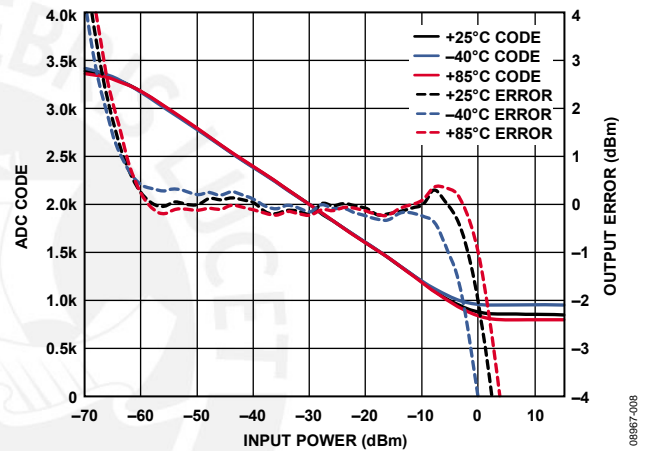


Figure 8. Input = 2.2 GHz, ADC Using an External 2.5 V Reference

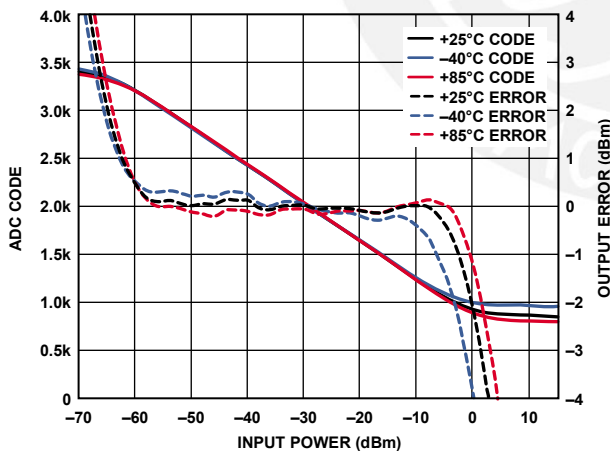


Figure 6. Input = 1.9 GHz, ADC Using an External 2.5 V Reference

### COMMON VARIATIONS

The [AD7887](#) is a 2-channel, 12-bit ADC with an SPI interface. The second input channel of this device can be connected to the [AD8318](#) TEMP pin. This provides a convenient measure of the ambient temperature around the [AD8318](#). Like the [AD8318](#) power measurement output, the TEMP voltage output should also be calibrated.

If the end application requires only a single channel, the 12-bit [AD7495](#) can be used. In multichannel applications that require multiple ADCs and DAC channels, the [AD7294](#) can be used. In addition to providing four 12-bit DAC outputs, this subsystem chip includes four uncommitted ADC channels, two high-side current sense inputs, and three temperature sensors. Current and temperature measurements are digitally converted and available to read over the I<sup>2</sup>C-compatible interface.

The temperature stability of the circuit can be improved using an external ADC reference. The [AD7887](#) internal 2.5 V reference has a 50 ppm/°C drift, which is approximately 15 mV over a 125°C range. Because the detector has a slope of -24 mV/dB, the ADC reference drift contributes approximately ±0.3 dB to the temperature drift error budget. The [AD8318](#) temperature drift is approximately ±0.5 dB over a similar temperature range. (This varies with frequency. See the [AD8318](#) data sheet for more details.)

If an external voltage reference is to be used, the [ADR421](#) 2.5 V reference is recommended. Its 1 ppm/°C temperature drift results in a reference voltage variation of only 312  $\mu\text{V}$  from  $-40^\circ\text{C}$  to  $+85^\circ\text{C}$ . This has a negligible effect on the overall temperature stability of the system.

If a less dynamic range is required, the [AD8317](#) (55 dB) or [AD8319](#) (45 dB) log detector can be used. If a true rms responding power measurement is required, the [AD8363](#) (50 dB) or [ADL5902](#) (65 dB) can be used.

## CIRCUIT EVALUATION AND TEST

This circuit uses the [EVAL-CN0150A-SDPZ](#) circuit board and the [EVAL-SDP-CB1Z System Demonstration Platform \(SDP\)](#) evaluation board. The two boards have 120-pin mating connectors, allowing for the quick setup and evaluation of the circuit's performance. The [EVAL-CN0150A-SDPZ](#) board contains the circuit to be evaluated, as described in this note, and the SDP evaluation board is used with the CN0150A evaluation software to capture the data from the [EVAL-CN0150A-SDPZ](#) circuit board.

### Equipment Needed

- PC with a USB port and Windows® XP or Windows Vista® (32-bit), or Windows 7 (32-bit)
- [EVAL-CN0150A-SDPZ](#) Circuit Evaluation Board
- [EVAL-SDP-CB1Z SDP](#) Evaluation Board
- CN0150A Evaluation Software
- Power supply: 6 V or 6 V wall wart
- Environmental chamber
- RF signal source
- Coaxial RF cable with SMA connectors

### Getting Started

Load the evaluation software by placing the CN0150A evaluation software CD in the CD drive of the PC. Using **My Computer**, locate the drive that contains the evaluation software CD and open the readme file. Follow the instructions contained in the readme file for installing and using the evaluation software.

### Functional Block Diagram

See Figure 1 of this circuit note for the circuit block diagram and the [EVAL-CN150A-SDPZ-SCH-Rev0.pdf](#) file for the circuit schematics. This file is contained in the [CN0150 Design Support Package](#).

### Setup

Connect the 120-pin connector on the [EVAL-CN0150A-SDPZ](#) circuit board to the CON A connector on the [EVAL-SDP-CB1Z](#) evaluation (SDP) board. Use nylon hardware to firmly secure the two boards, using the holes provided at the ends of the 120-pin connectors. Using an appropriate RF cable, connect the RF signal source to the [EVAL-CN0150A-SDPZ](#) board via the SMA RF input connector. With power to the supply off, connect a 6 V power supply to the +6V and GND pins on the board. If available, a

6 V wall wart can be connected to the barrel connector on the board and used in place of the 6 V power supply. Connect the USB cable supplied with the SDP board to the USB port on the PC. Note: Do not connect the USB cable to the mini USB connector on the SDP board at this time.

### Test

Apply power to the 6 V supply (or wall wart) connected to [EVAL-CN0150A-SDPZ](#) circuit board. Launch the evaluation software and connect the USB cable from the PC to the USB mini connector on the SDP board.

Once USB communications are established, the SDP board can now be used to send, receive, and capture serial data from the [EVAL-CN0150A-SDPZ](#) board.

The data in this circuit note were generated using a Rohde & Schwarz SMT-03 RF signal source and an Agilent E3631A power supply. The signal source was set to the frequencies indicated in the graphs, and the input power was stepped and data recorded in 1 dB increments.

Temperature testing was performed using a Test Equity Model 107 environmental chamber. The [EVAL-CN0150A-SDPZ](#) evaluation board was placed in the chamber via a slot in the test chamber door, with the SDP evaluation board extending outside.

Information and details regarding how to use the evaluation software for data capture can be found in the CN0150A evaluation software readme file.

Information regarding the SDP board can be found in the [SDP User Guide](#).

## LEARN MORE

[CN0150 Design Support Package:](#)

<http://www.analog.com/CN0150-DesignSupport>

[SDP User Guide](#)

[MT-031 Tutorial, Grounding Data Converters and Solving the Mystery of "AGND" and "DGND," Analog Devices.](#)

[MT-077 Tutorial, Log Amp Basics, Analog Devices.](#)

[MT-078 Tutorial, High Speed Log Amps, Analog Devices.](#)

[MT-101 Tutorial, Decoupling Techniques, Analog Devices.](#)

[Whitlow, Dana. Design and Operation of Automatic Gain Control Loops for Receivers in Modern Communications Systems. Chapter 8. Analog Devices Wireless Seminar. 2006.](#)

## Data Sheets and Evaluation Boards

[CN-0150 Circuit Evaluation Board \(EVAL-CN0150A-SDPZ\)](#)

[System Demonstration Platform \(EVAL-SDP-CB1Z\)](#)

[AD7887 Data Sheet](#)

[AD7887 Evaluation Board](#)

[AD8318 Data Sheet](#)

[AD8318 Evaluation Board](#)

[ADR421 Data Sheet](#)

# Circuit Note

## REVISION HISTORY

### 2/12—Rev. B to Rev. C

Changed 70 dB to 60 dB in Circuit Note Title ..... 1

### 3/11—Rev. A to Rev. B

Added Evaluation and Design Support Section ..... 1

Added Circuit Evaluation and Test Section ..... 4

### 8/10— Rev. 0 to Rev. A

Changes to the Circuit Function and Benefits Section ..... 1

Changes to the Circuit Description Section ..... 2

Changes to the Common Variations Section ..... 4

### 4/10—Revision 0: Initial Version



I<sup>2</sup>C refers to a communications protocol originally developed by Philips Semiconductors (now NXP Semiconductors).

(Continued from first page) Circuits from the Lab circuits are intended only for use with Analog Devices products and are the intellectual property of Analog Devices or its licensors. While you may use the Circuits from the Lab circuits in the design of your product, no other license is granted by implication or otherwise under any patents or other intellectual property by application or use of the Circuits from the Lab circuits. Information furnished by Analog Devices is believed to be accurate and reliable. However, Circuits from the Lab circuits are supplied "as is" and without warranties of any kind, express, implied, or statutory including, but not limited to, any implied warranty of merchantability, noninfringement or fitness for a particular purpose and no responsibility is assumed by Analog Devices for their use, nor for any infringements of patents or other rights of third parties that may result from their use. Analog Devices reserves the right to change any Circuits from the Lab circuits at any time without notice but is under no obligation to do so.

©2010–2012 Analog Devices, Inc. All rights reserved. Trademarks and registered trademarks are the property of their respective owners.  
CN08967-0-2/12(C)



www.analog.com

**Circuits  
from the Lab™**  
Reference Circuits

Circuits from the Lab™ reference circuits are engineered and tested for quick and easy system integration to help solve today's analog, mixed-signal, and RF design challenges. For more information and/or support, visit [www.analog.com/CN0178](http://www.analog.com/CN0178).

**Devices Connected/Referenced**

<b>ADL5902</b>	50 MHz to 9 GHz, 65 dB TruPwr™ Detector
<b>AD7466</b>	Micropower, 12-Bit, 200 kSPS SAR ADC

**Software-Calibrated, 50 MHz to 9 GHz, RF Power Measurement System**

**EVALUATION AND DESIGN SUPPORT**

**Circuit Evaluation Boards**

- [CN-0178 Circuit Evaluation Board \(EVAL-CN0178-SDPZ\)](#)
- [System Demonstration Platform \(EVAL-SDP-CB1Z\)](#)

**Design and Integration Files**

- [Schematics, Layout Files, Bill of Materials](#)

**CIRCUIT FUNCTION AND BENEFITS**

This circuit uses the **ADL5902** TruPwr™ detector to measure the rms signal strength of RF signals with varying crest factors (peak-to-average ratio) over a dynamic range of approximately 65 dB and operates at frequencies from 50 MHz up to 9 GHz.

The measurement result is provided as serial data at the output of a 12-bit ADC (**AD7466**). A simple 4-point system calibration at ambient temperature is performed in the digital domain.

The interface between the RF detector and the ADC is straightforward, consisting of two signal scaling resistors and no active components. In addition, the ADL5902 internal 2.3 V reference voltage provides the supply and reference voltage for the micropower ADC. The AD7466 has no pipeline delay and is operated as a read-only SAR ADC.

The overall circuit achieves temperature stability of approximately ±0.5 dB.

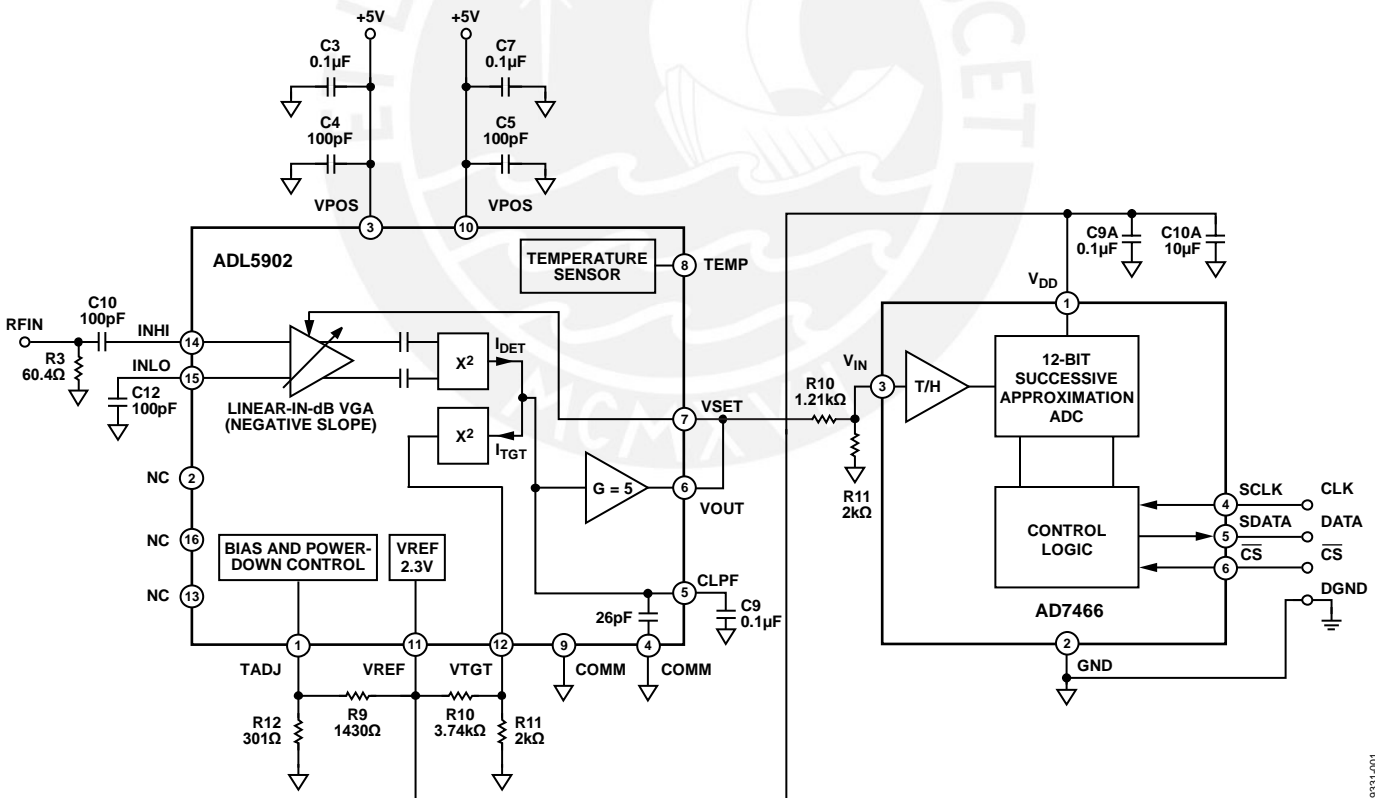


Figure 1. Software-Calibrated RF Power Measurement System

**Rev.A**

Circuits from the Lab™ circuits from Analog Devices have been designed and built by Analog Devices engineers. Standard engineering practices have been employed in the design and construction of each circuit, and their function and performance have been tested and verified in a lab environment at room temperature. However, you are solely responsible for testing the circuit and determining its suitability and applicability for your use and application. Accordingly, in no event shall Analog Devices be liable for direct, indirect, special, incidental, consequential or punitive damages due to any cause whatsoever connected to the use of any Circuits from the Lab circuits. (Continued on last page)

One Technology Way, P.O. Box 9106, Norwood, MA 02062-9106, U.S.A.  
 Tel: 781.329.4700 [www.analog.com](http://www.analog.com)  
 Fax: 781.461.3113 ©2010–2011 Analog Devices, Inc. All rights reserved.

Data is shown for the two devices operating over a  $-40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$  temperature range.

**CIRCUIT DESCRIPTION**

The RF signal being measured is applied to the input of the ADL5902, a linear-in-dB rms-responding rms detector. The external  $60.4\ \Omega$  resistor, R3, combined with the relatively high input impedance of the ADL5902 ensures a broadband  $50\ \Omega$  match to the RF input. The ADL5902 is configured in its so-called “measurement mode,” with the VSET and VOUT pins connected together. In this mode the output voltage is proportional to the logarithm of the rms value of the input. In other words, the reading is presented directly in decibels and is scaled to 1.06 V per decade, or 53 mV/dB.

The power supply voltage and reference voltage for the AD7466 12-bit ADC are provided by the ADL5902 internal 2.3 V reference. Because the AD7466 consumes so little current ( $16\ \mu\text{A}$  when sampling at 10 kSPS), the ADL5902’s reference voltage output can supply the ADC, as well as the temperature compensating and rms accuracy-scaling network consisting of R9, R10, R11, and R12.

The ADC full-scale voltage is equal to 2.3 V. The maximum detector output voltage (when operating in its linear input range) is approximately 3.5 V (see ADL5902 data sheet figures 6, 7, 8, 12, 13, and 14) and must, therefore, be scaled down by a factor of 0.657 before driving the AD7466. This scaling is implemented using a simple resistor divider R10 and R11 ( $1.21\ \text{k}\Omega$  and  $2.0\ \text{k}\Omega$ ). These values provide an actual scaling factor of 0.623, which ensures that the ADL5902 RF detector does not overdrive the ADC by building in some room for resistor tolerance.

A typical plot of detector output voltage vs. input power is shown in Figure 2 (without output scaling).

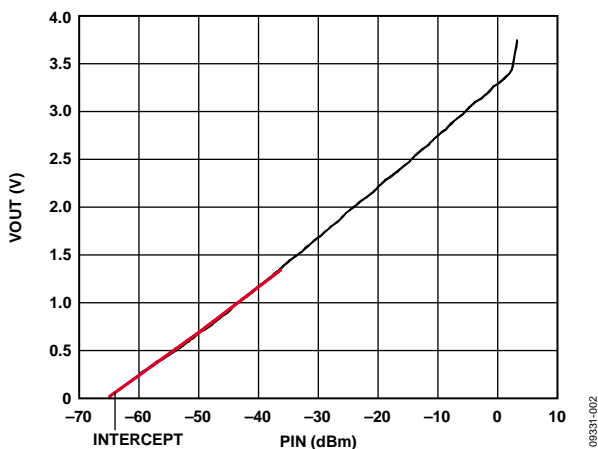


Figure 2. ADL5902 RMS Detector, Output Voltage vs. Input Power @ 900 MHz

The transfer function of the detector can be approximated by the equation

$$VOUT = SLOPE\_DETECTOR \times (PIN - INTERCEPT)$$

where  $SLOPE\_DETECTOR$  is in mV/dB;  $INTERCEPT$  is the x-axis intercept with a unit of dBm;  $PIN$  is the input power in dBm.

At the output of the ADC,  $VOUT$  is replaced by the ADC’s output code, and the equation can be rewritten as

$$CODE = SLOPE \times (PIN - INTERCEPT)$$

where  $SLOPE$  is the combined slope of the detector, the scaling resistors, and the ADC, and has the unit of counts/dB;  $PIN$  and  $INTERCEPT$  still have the unit of dBm.

Figure 3 shows a typical detector power sweep in terms of input power and observed ADC output codes for a 700 MHz input signal.

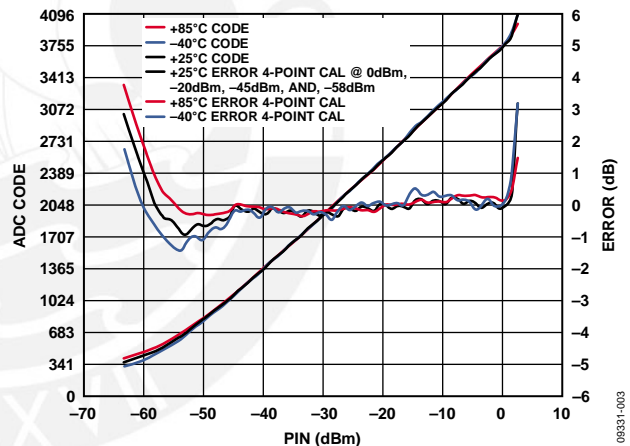


Figure 3. ADC Output Code and Error vs. RF Input Power @ 700 MHz

Overall  $SLOPE$  and  $INTERCEPT$  will vary from system to system. This variation is caused by part to part variations in the transfer function of the RF detector, the scaling resistors, and the ADC. As a result, a system level calibration is required to determine the complete system  $SLOPE$  and  $INTERCEPT$ . In this application, a 4-point calibration is used to correct for some nonlinearity in the RF detector’s transfer function, particularly at the low end. This 4-point calibration scheme yields three  $SLOPE$  and three  $INTERCEPT$  calibration coefficients, which should be stored in nonvolatile RAM (NVM) after calibration.

The calibration is performed by applying four known signal levels to the ADL5902 and measuring the corresponding output codes from the ADC. The calibration points chosen should be within the linear operating range of the device. In this example, calibration points at 0 dBm, -20 dBm, -45 dBm, and -58 dBm were used.

The *SLOPE* and *INTERCEPT* calibration coefficients are calculated using the equations

$$SLOPE1 = (CODE_1 - CODE_2)/(PIN_1 - PIN_2)$$

$$INTERCEPT1 = CODE_1/(SLOPE_ADC \times PIN_1)$$

This calculation is then repeated using *CODE\_2/CODE\_3* and *CODE\_3/CODE\_4* to calculate *SLOPE2/INTERCEPT2* and *SLOPE3/INTERCEPT3*, respectively. The six calibration coefficients should then be stored in NVM along with *CODE\_1*, *CODE\_2*, *CODE\_3*, and *CODE\_4*.

When the circuit is in operation in the field, these calibration coefficients are used to calculate an unknown input power level, *PIN*, using the equation

$$PIN = (CODE/SLOPE) + INTERCEPT$$

In order to retrieve the appropriate *SLOPE* and *INTERCEPT* calibration coefficients during circuit operation, the observed *CODE* from the ADC must be compared to *CODE\_1*, *CODE\_2*, *CODE\_3*, and *CODE\_4*. For example if the *CODE* from the ADC is between *CODE\_1* and *CODE\_2*, then the *SLOPE1* and *INTERCEPT1* should be used. This step can also be used to provide an underrange or overrange warning. For example, if the *CODE* from the ADC is greater than *CODE\_1* or less than *CODE\_4*, it indicates that the measured power is outside of the calibration range

Figure 3 also shows the transfer function variation of the circuit vs. the above straight line equations. This error function is caused by bending at the edges of the transfer function, small ripple in the linear operating range, and drift over temperature. The error is expressed in dB using the equation

$$\begin{aligned} Error (dB) &= Calculated RF Power - True Input Power \\ &= (CODE/SLOPE) + INTERCEPT - PIN_{TRUE} \end{aligned}$$

Figure 3 also includes plots of error vs. temperature. In this case the measured ADC codes at +85°C and -40°C are compared to the straight line equations at ambient. This is consistent with a real world system where system calibration is generally only practical at ambient temperature.

Figure 4 and Figure 5 show the performance of the circuit at 1 GHz and 2.2 GHz, respectively.

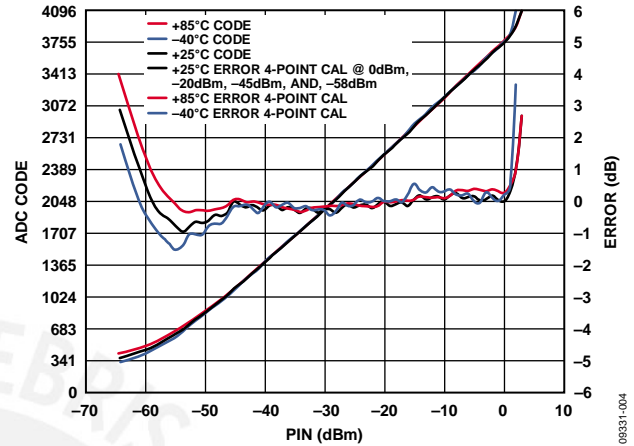


Figure 4. ADC Output Code and Error vs. RF Input Power @ 1 GHz

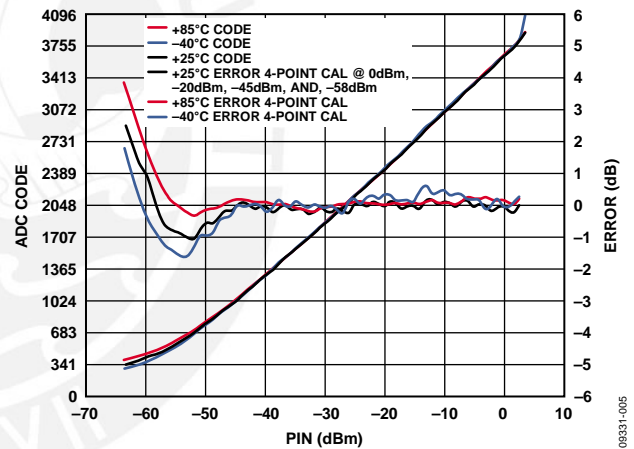


Figure 5. ADC Output Code and Error vs. RF Input Power @ 2.2 GHz

The performance of this or any high speed circuit is highly dependent on proper PCB layout. This includes, but is not limited to, power supply bypassing, controlled impedance lines (where required), component placement, signal routing, and power and ground planes. (See [MT-031 Tutorial](#), [MT-101 Tutorial](#), and article, [A Practical Guide to High-Speed Printed-Circuit-Board Layout](#), for more detailed information regarding PCB layout.)

A complete design support package for this circuit note can be found at [www.analog.com/CN0178-DesignSupport](http://www.analog.com/CN0178-DesignSupport).



## COMMON VARIATIONS

For applications that require less RF detection range, the [AD8363](#) rms detector can be used. The AD8363 has a detection range of 50 dB and operates at frequencies up to 6 GHz. For non-rms detection applications, the [AD8317/AD8318/AD8319](#) or [ADL5513](#) can be used. These devices offer varying detection ranges and have varying input frequency ranges up to 10 GHz (see [CN-0150](#) for more details).

The AD7466 is a single channel, 12-bit ADC with SPI interface. If the end application requires a multichannel ADC, the dual 12-bit [AD7887](#) can be used. In multichannel applications that require multiple ADC and DAC channels, the [AD7294](#) can be used. In addition to providing four 12-bit DAC outputs, this subsystem chip includes four uncommitted ADC channels, two high-side current sense inputs, and three temperature sensors. Current and temperature measurements are digitally converted and available to read over the I<sup>2</sup>C-compatible interface.

## CIRCUIT EVALUATION AND TEST

This circuit uses the EVAL-CN0178-SDPZ circuit board and the EVAL-SDP-CB1Z System Demonstration Platform (SDP) evaluation board. The two boards have 120-pin mating connectors, allowing for the quick setup and evaluation of the circuit's performance. The EVAL-CN0178-SDPZ board contains the circuit to be evaluated, as described in this note, and the SDP evaluation board is used with the CN0178 evaluation software to capture the data from the EVAL-CN0178-SDPZ circuit board.

### Equipment Needed

- PC with a USB port and Windows® XP or Windows Vista® (32-bit), or Windows® 7 (32-bit)
- EVAL-CN0178-SDPZ Circuit Evaluation Board
- EVAL-SDP-CB1Z SDP Evaluation Board
- CN0178 Evaluation Software
- Power supply: +6 V, or +6 V "wall wart"
- Environmental chamber
- RF signal source
- Coaxial RF cable with SMA connectors

### Getting Started

Load the evaluation software by placing the CN0178 Evaluation Software disc in the CD drive of the PC. Using "My Computer," locate the drive that contains the evaluation software disc and open the Readme file. Follow the instructions contained in the Readme file for installing and using the evaluation software.

### Functional Block Diagram

See Figure 1 of this circuit note for the circuit block diagram, and the file "EVAL-CN0178-SDPZ-SCH-Rev0.pdf" for the circuit schematics. This file is contained in the [CN0178 Design Support Package](#).

### Setup

Connect the 120-pin connector on the EVAL-CN0178-SDPZ circuit board to the connector marked "CON A" on the EVAL-SDP-CB1Z evaluation (SDP) board. Nylon hardware should be used to firmly secure the two boards, using the holes provided at the ends of the 120-pin connectors. Using an appropriate RF cable, connect the RF signal source to the EVAL-CN0178-SDPZ board via the SMA RF input connector. With power to the supply off, connect a +6 V power supply to the pins marked "+6 V" and "GND" on the board. If available, a +6 V "wall wart" can be connected to the barrel connector on the board and used in place of the +6 V power supply. Connect the USB cable supplied with the SDP board to the USB port on the PC. Note: Do not connect the USB cable to the mini USB connector on the SDP board at this time.

### Test

Apply power to the +6 V supply (or "wall wart") connected to EVAL-CN0178-SDPZ circuit board. Launch the Evaluation software, and connect the USB cable from the PC to the USB mini-connector on the SDP board.

Once USB communications are established, the SDP board can now be used to send, receive, and capture serial data from the EVAL-CN0178-SDPZ board.

The data in this circuit note were generated using a Rohde & Schwarz SMT-03 RF signal source, and an Agilent E3631A power supply. The signal source was set to the frequencies indicated in the graphs, and the input power was stepped and data recorded in 1 dB increments.

Temperature testing was performed using a Test Equity Model 107 environmental chamber. The CN0178-SDPZ evaluation board was placed in the chamber via a slot in the test chamber door, with the SDP evaluation board extending outside.

Information and details regarding how to use the evaluation software for data capture can be found in the CN0178 Evaluation Software ReadMe file.

Information regarding the SDP board can be found in the [SDP User Guide](#).

**LEARN MORE**

CN0178 Design Support Package:  
<http://www.analog.com/CN0178-DesignSupport>  
 SDP User Guide

Ardizzoni, John. *A Practical Guide to High-Speed Printed-Circuit-Board Layout*, Analog Dialogue 39-09, September 2005.

CN-0150 Circuit Note, *Software-Calibrated, 1 MHz to 8 GHz, 70 dB RF Power Measurement System Using the AD8318 Logarithmic Detector*, Analog Devices.

MT-031 Tutorial, *Grounding Data Converters and Solving the Mystery of "AGND" and "DGND"*, Analog Devices.

MT-073 Tutorial, *High Speed Variable Gain Amplifiers (VGAs)*, Analog Devices.

MT-077 Tutorial, *Log Amp Basics*, Analog Devices.

MT-078 Tutorial, *High Speed Log Amps*, Analog Devices.

MT-081 Tutorial, *RMS-to-DC Converters*, Analog Devices.

MT-101 Tutorial, *Decoupling Techniques*, Analog Devices.

Whitlow, Dana. *Design and Operation of Automatic Gain Control Loops for Receivers in Modern Communications Systems*. Chapter 8. Analog Devices Wireless Seminar. 2006.

**Data Sheets and Evaluation Boards**

CN-0178 Circuit Evaluation Board (EVAL-CN0178-SDPZ)  
 System Demonstration Platform (EVAL-SDP-CB1Z)  
 ADL5902 Data Sheet  
 ADL5902 Evaluation Board  
 AD7466 Data Sheet  
 AD7466 Evaluation Board

**REVISION HISTORY****3/11—Rev. 0 to Rev. A**

Added Evaluation and Design Support Section..... 1  
 Added Circuit Evaluation and Test Section..... 4

**10/10—Rev. 0: Initial Version**

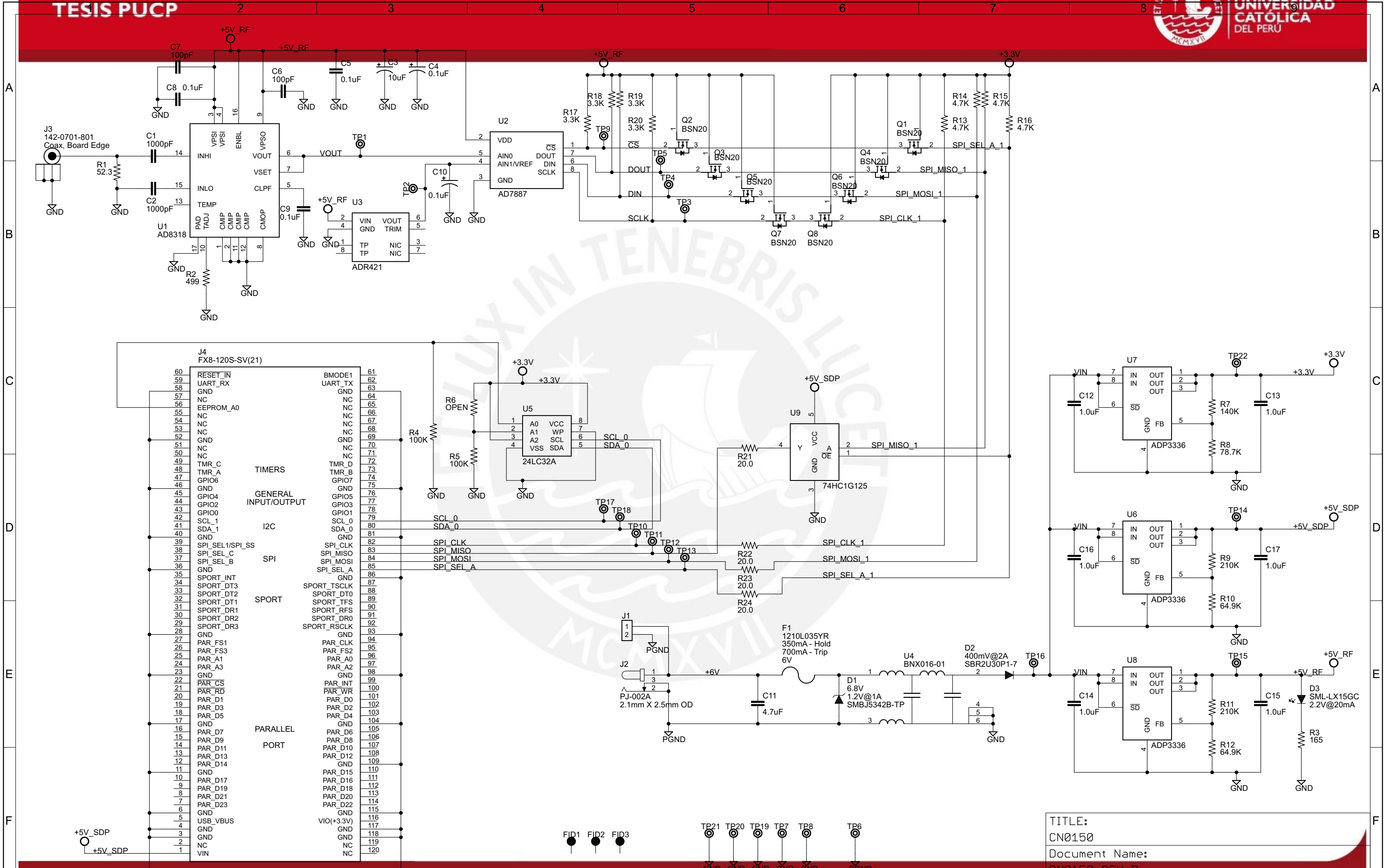
I<sup>2</sup>C refers to a communications protocol originally developed by Philips Semiconductors (now NXP Semiconductors).

(Continued from first page) Circuits from the Lab circuits are intended only for use with Analog Devices products and are the intellectual property of Analog Devices or its licensors. While you may use the Circuits from the Lab circuits in the design of your product, no other license is granted by implication or otherwise under any patents or other intellectual property by application or use of the Circuits from the Lab circuits. Information furnished by Analog Devices is believed to be accurate and reliable. However, "Circuits from the Lab" are supplied "as is" and without warranties of any kind, express, implied, or statutory including, but not limited to, any implied warranty of merchantability, noninfringement or fitness for a particular purpose and no responsibility is assumed by Analog Devices for their use, nor for any infringements of patents or other rights of third parties that may result from their use. Analog Devices reserves the right to change any Circuits from the Lab circuits at any time without notice but is under no obligation to do so.

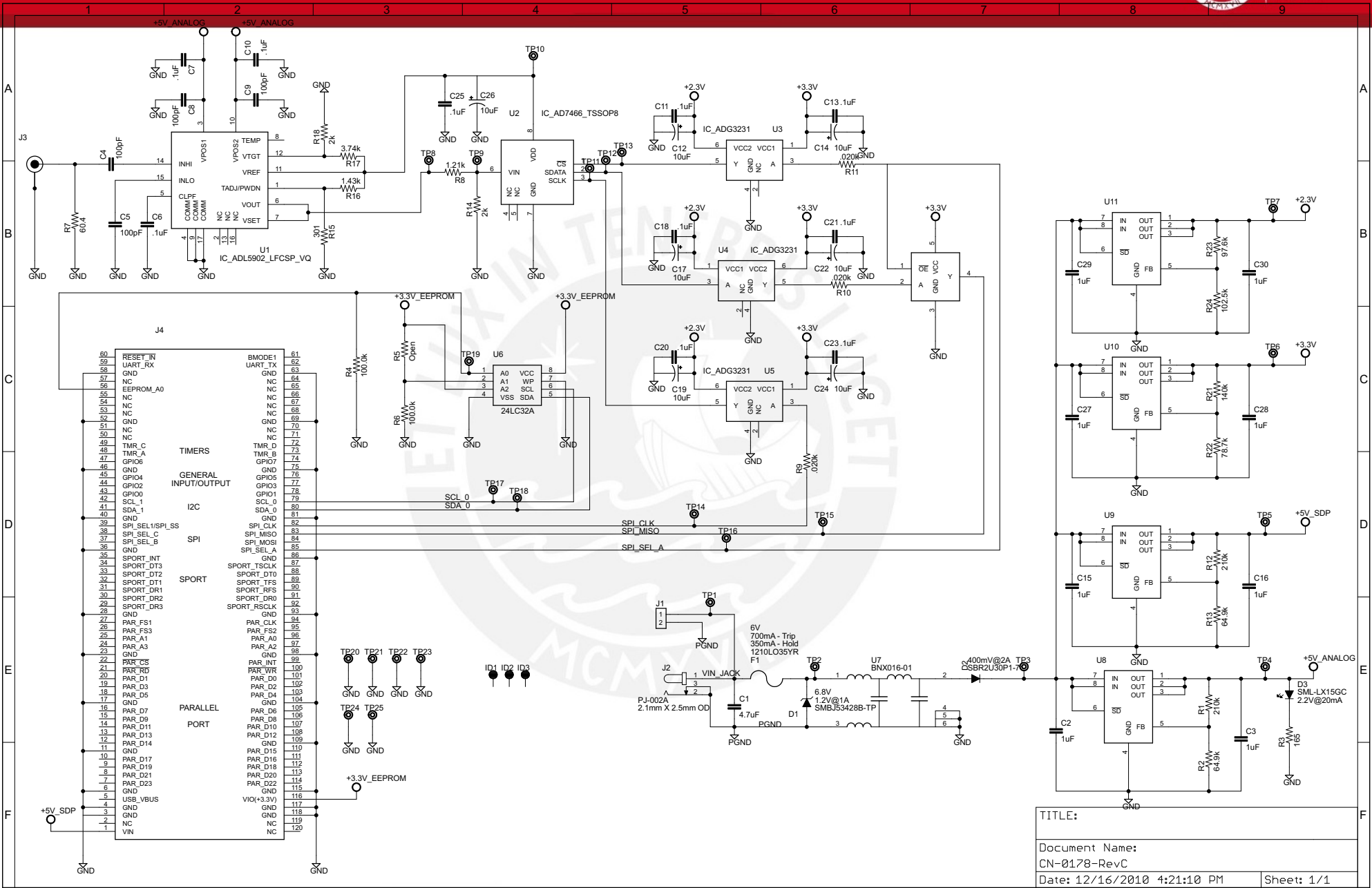
©2010–2011 Analog Devices, Inc. All rights reserved. Trademarks and registered trademarks are the property of their respective owners.  
 CN09331-0-3/11(A)



[www.analog.com](http://www.analog.com)

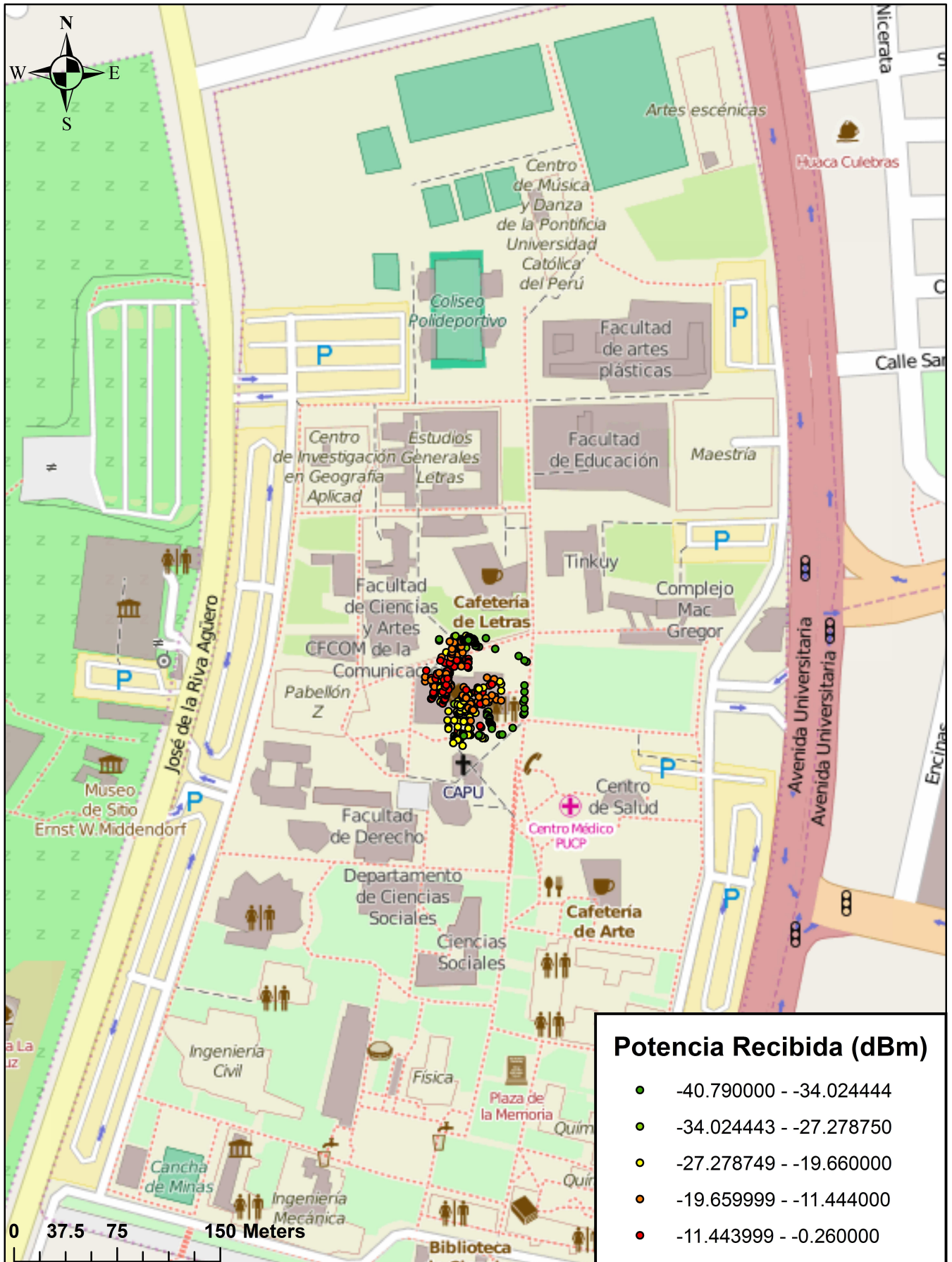


TITLE:	CN0150
Document Name:	CN0150-SCH-B
Date:	12/6/2010 3:00:39 PM
Sheet:	1/1

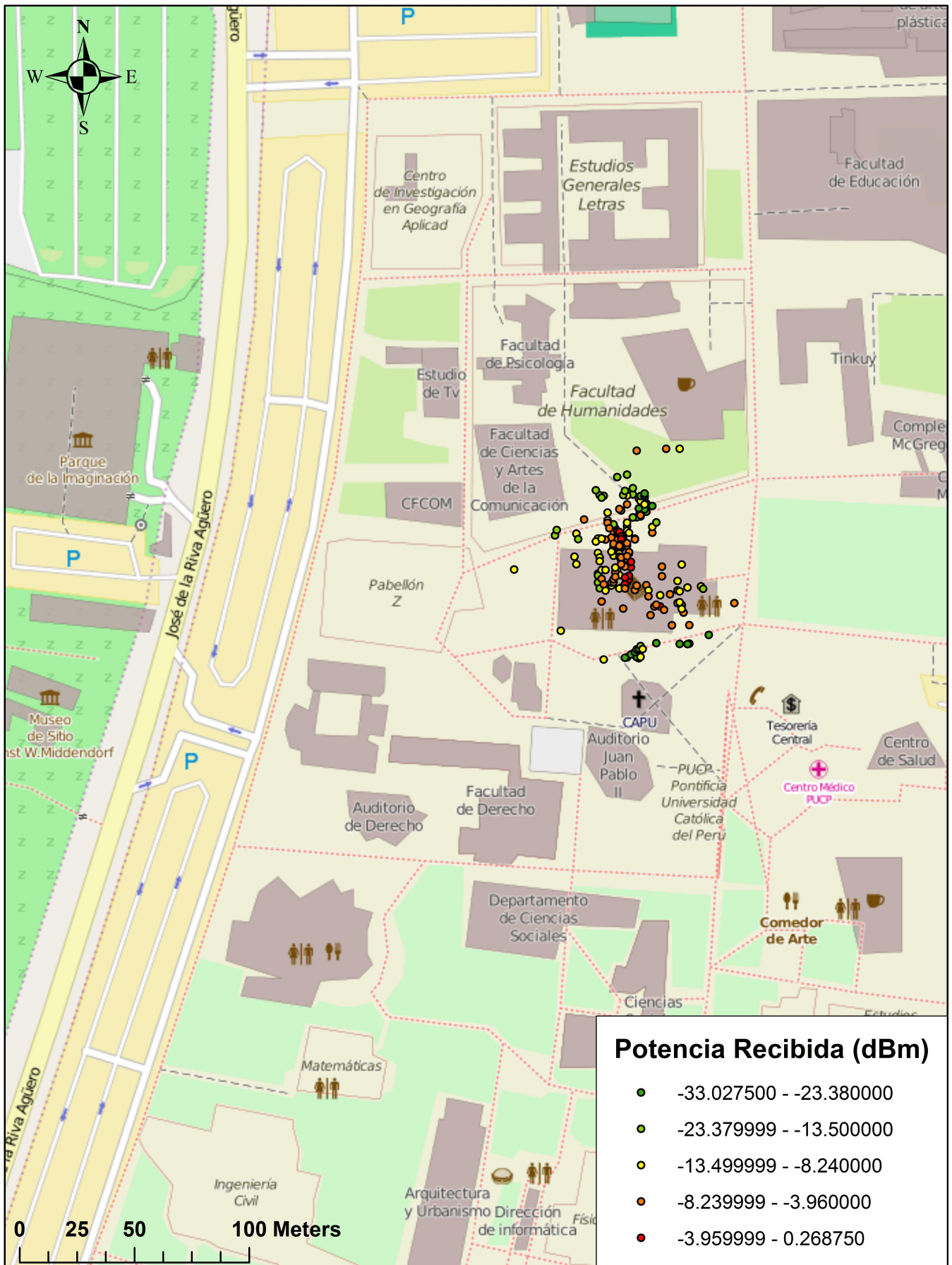


TITLE:
Document Name: CN-0178-RevC
Date: 12/16/2010 4:21:10 PM
Sheet: 1/1

# Medición con la antena de retorno de 1900 MHz



# Medición con la antena de retorno de 850 MHz



## GUIA DE USO DEL ANALIZADOR DE CAMPOS ELECTROMAGNÉTICOS SRM-3006 DEL NARDA SAFETY TEST SOLUTIONS

A continuación se describirán los pasos realizados a la hora de analizar los puntos medidos por el equipo SRM-3006.

1. El equipo viene con el software SRM-3006\_Tools, el cual te permite realizar operaciones básicas como la de configurar el equipo según la medición a realizar, descargar y visualizar los datos almacenados en el equipo, entre otras opciones básicas. Como se necesita trabajar con los datos almacenados, se necesita descargar el software SRM-3006\_TS, el cual te permite una evaluación de los datos, para el caso de la presente tesis, te permite realizar la integración del todo el rango medido.
2. Una vez descargo el software e importado todos los puntos medidos almacenados en el equipo (en formato .CSV), se procederá a trabajar con las mediciones. Para ello se debe crear una database en formato .srmdb, realizando los siguientes pasos: File>New>Database como se observa en la figura 1.

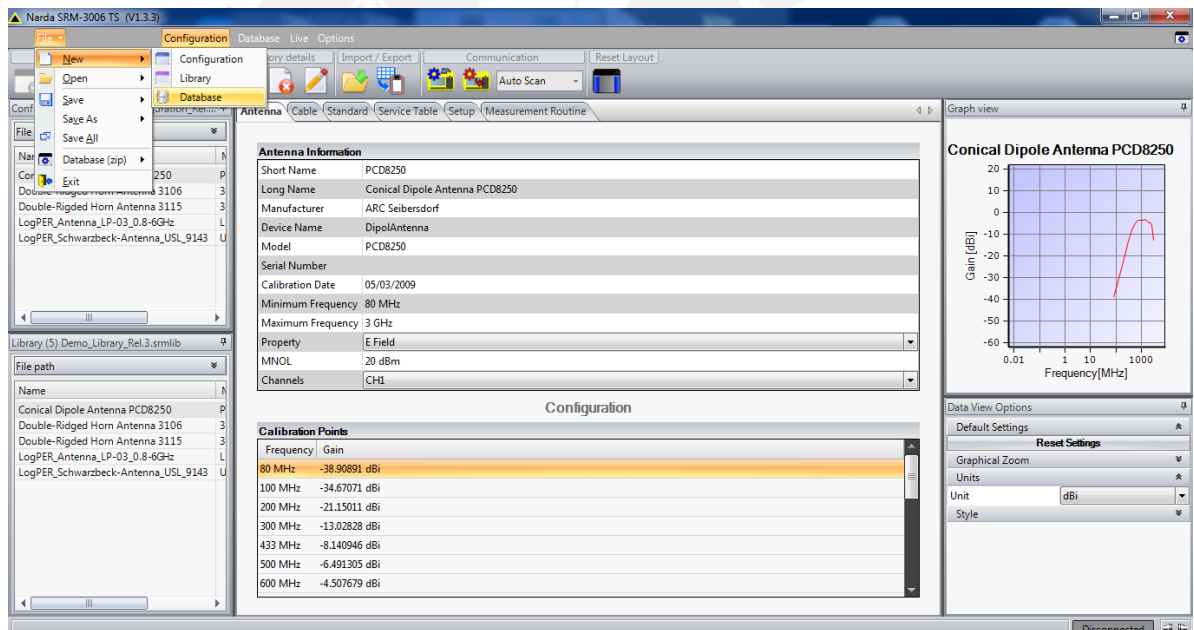
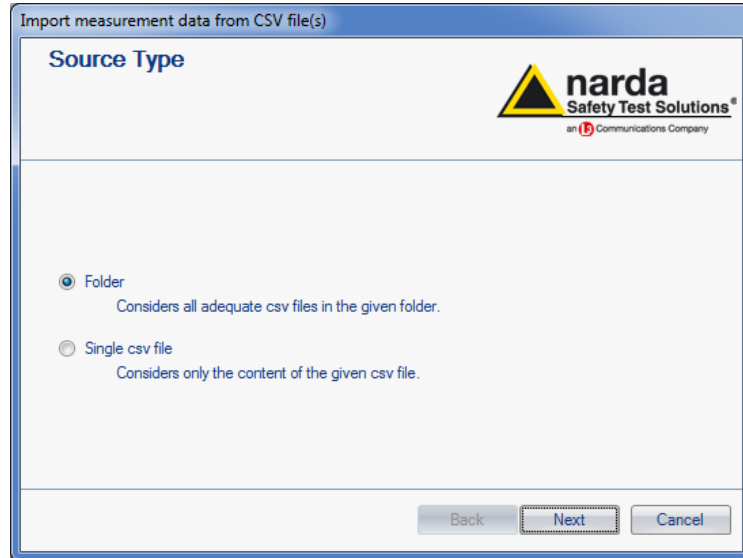


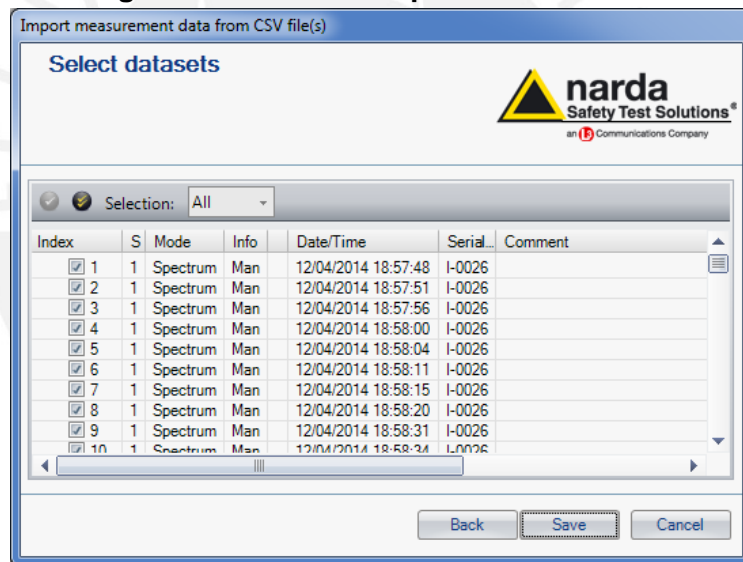
Figura 1: Creación de una database en el software SRM-3006\_TS

3. Luego de haber creado la database, se procederá a almacenar toda la data importada del analizador dentro del archivo .srmdb creado. Para ello en la pestaña Database debajo del pestaña Import/Export se encuentra la opción Data. Luego de darle clic, se abrirá el cuadro de la figura 2. Allí se selecciona Folder, ya que en mi caso importe una gran cantidad de datos y los almacené una carpeta (folder), luego seleccionas la ubicación del folder y finalmente te aparecerá la figura 3, con

todos los datos que se encontraron en tu folder. Seleccionas lo que se requieren, en mi caso todo, y le das a la opción Save.



**Figura 2: Cuadro de importación de datos**



**Figura 3: Cuadro de selección de datos a analizar**

- Luego se empezaran a importar toda la data seleccionada (figura 4) y se podrá visualizar cada punto medido en la parte inferior izquierda, en el cuadro Database. Finalmente se selecciona el dato y en la esquina derecha inferior se encuentra habilitada el cuadro de Evaluation, en donde se encuentra la opción Integration. Se puede realizar la integración de manera manual en la misma grafica o bien seleccionando una frecuencia de integración mínima o máxima (figura 5).



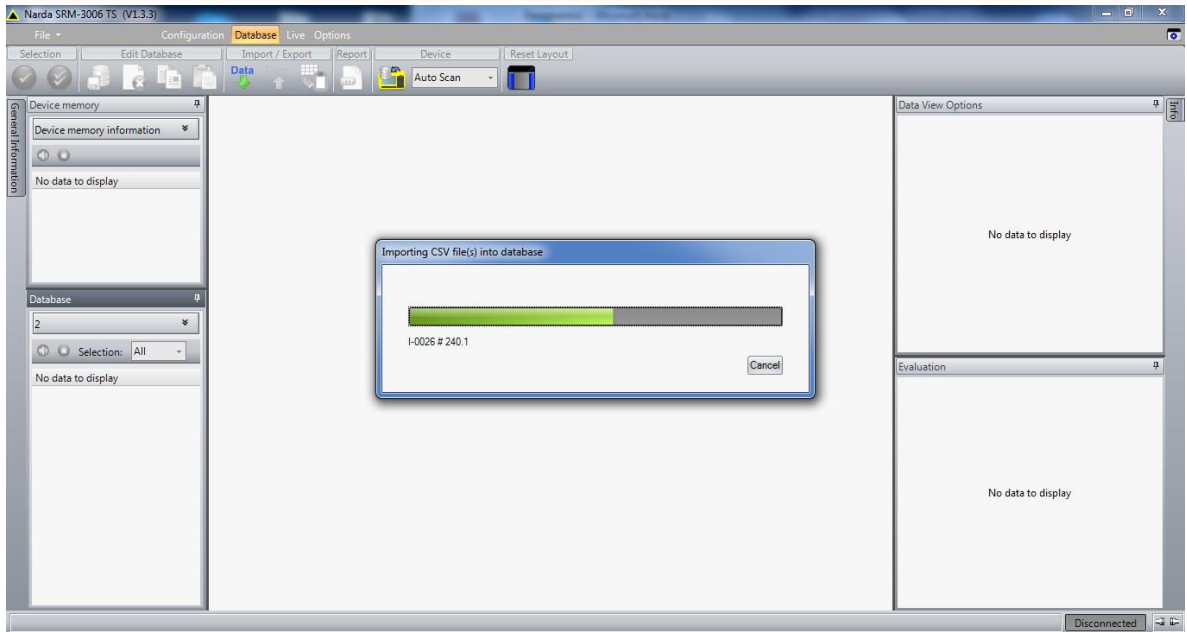


Figura 4: Importación de los datos en la archivo database creado

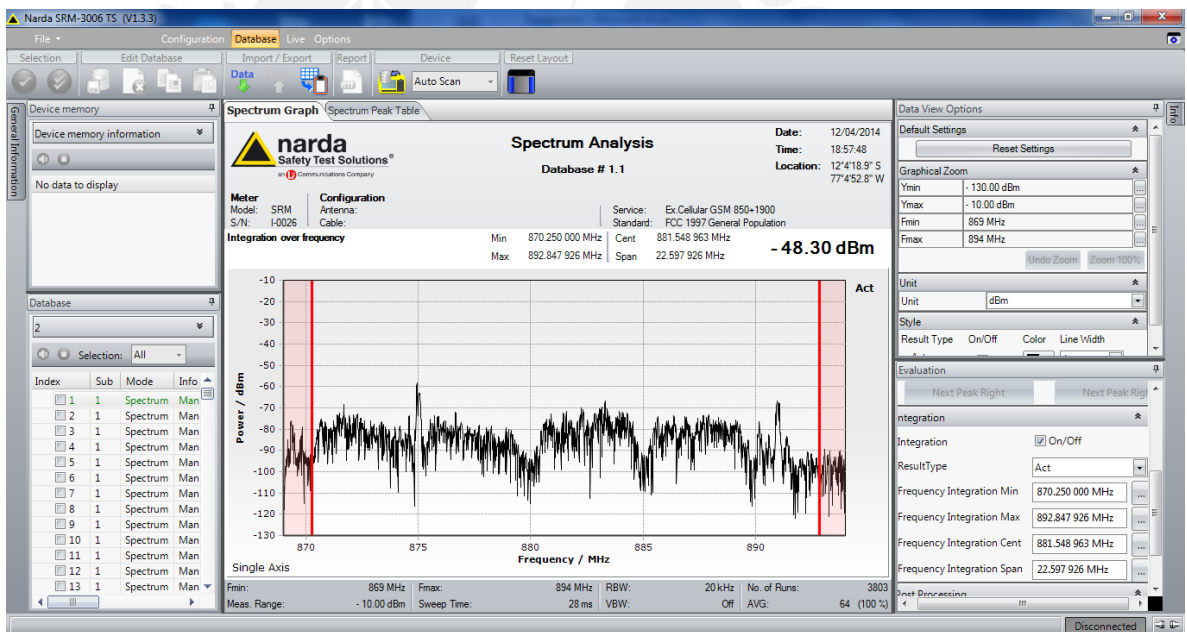


Figura 5: Evaluación de uno de los datos importados

Elaborado por Giancarlo Villena Prado

## RESULTADOS DE LAS PRUEBAS DEL SISTEMA

Como se mencionó en el documento de tesis, los resultados fueron analizados a través de la herramienta API de Google Maps. A continuación se escribirán los URL's donde se puede analizar con mayor detalle cada punto analizado según la prueba realizada:

### 1. Pruebas realizadas a nivel del suelo:

- **Prueba con la antena de retorno de 850 MHz**

[https://www.google.com/fusiontables/DataSource?docid=1vIPy-IPD416j\\_5FfYPz\\_-rczxCwhib-JDq4x2bUX#map:id=3](https://www.google.com/fusiontables/DataSource?docid=1vIPy-IPD416j_5FfYPz_-rczxCwhib-JDq4x2bUX#map:id=3)

- **Prueba con la antena de retorno de 1900 MHz**

[https://www.google.com/fusiontables/DataSource?docid=1xHSgUc9fNnzYJ-eid7jwPIHdhL7ScaOS0\\_4vcYsO&pli=1#map:id=3](https://www.google.com/fusiontables/DataSource?docid=1xHSgUc9fNnzYJ-eid7jwPIHdhL7ScaOS0_4vcYsO&pli=1#map:id=3)

### 2. Pruebas realizadas en el drone alrededor de la antena de telefonía celular:

- **Prueba con la antena de retorno de 850 MHz**

<https://www.google.com/fusiontables/DataSource?docid=1bcl5O7JU-rGrXqTD2Pyfwg5di53QpBS6n-0CMVR6#map:id=3>

- **Prueba con la antena de retorno de 1900 MHz**

[https://www.google.com/fusiontables/DataSource?docid=1tgQ1\\_rEmwQhw8svLCCdyuGjq7zc1UV2Z2-RNrD57&pli=1#map:id=3](https://www.google.com/fusiontables/DataSource?docid=1tgQ1_rEmwQhw8svLCCdyuGjq7zc1UV2Z2-RNrD57&pli=1#map:id=3)